

Single N-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

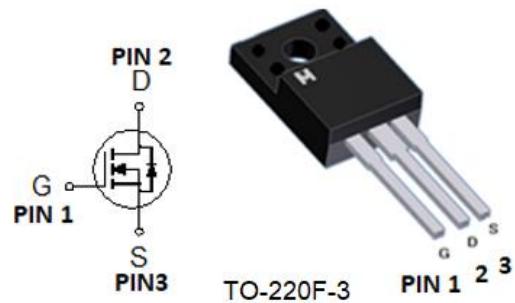
BV _{DSS}	250V
R _{DSON} (MAX.)	0.22Ω
I _D	18A

Single N Channel MOSFET

UIS, Rg 100% Tested

Pb-Free Lead Plating & Halogen Free

Pin Description:



ABSOLUTE MAXIMUM RATINGS (T_c = 25 °C Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V _{GS}	±30	V
Continuous Drain Current	T _c = 25 °C	I _D	18	A
	T _c = 100 °C		8	
Pulsed Drain Current ¹		I _{DM}	45	
Avalanche Current		I _{AS}	10	
Avalanche Energy	L = 1mH, ID=10A, RG=25Ω	E _{AS}	50	mJ
Repetitive Avalanche Energy ²	L = 0.5mH	E _{AR}	25	
Power Dissipation	T _c = 25 °C	P _D	38	W
	T _c = 100 °C		15	
Operating Junction & Storage Temperature Range		T _j , T _{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	R _{θJC}	3.3	65	°C / W
Junction-to-Ambient	R _{θJA}			

¹Pulse width limited by maximum junction temperature.

²Duty cycle ≤ 1%

³Pulsed drain current rating is package limited

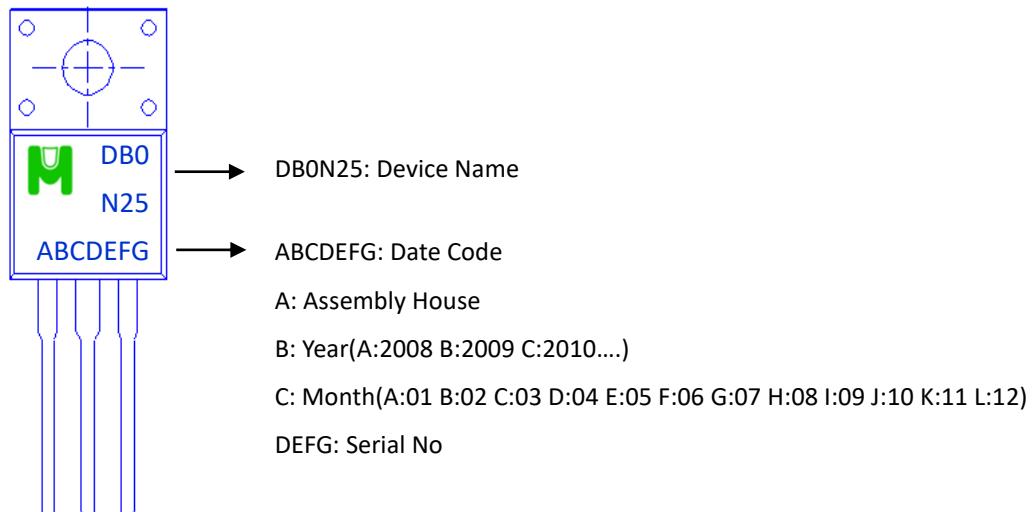
ELECTRICAL CHARACTERISTICS ($T_c = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0V, I_D = 10\text{mA}$	250			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	2.0	3.7	4.5	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 30V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 200V, V_{GS} = 0V$			1	μA
		$V_{DS} = 200V, V_{GS} = 0V, T_J = 125^\circ\text{C}$			25	
On-State Drain Current ¹	$I_{D(\text{ON})}$	$V_{DS} = 10V, V_{GS} = 10V$	18			A
Drain-Source On-State Resistance ¹	$R_{DS(\text{ON})}$	$V_{GS} = 10V, I_D = 9A$		0.19	0.22	Ω
Forward Transconductance ¹	g_{fs}	$V_{DS} = 10V, I_D = 9A$		18		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 25V, f = 1\text{MHz}$		3740		pF
Output Capacitance	C_{oss}			127		
Reverse Transfer Capacitance	C_{rss}			72		
Gate Resistance	R_g	$V_{GS} = 15\text{mV}, V_{DS} = 0V, f = 1\text{MHz}$		1.7		Ω
Total Gate Charge ^{1,2}	Q_g	$V_{DS} = 200V, V_{GS} = 10V, I_D = 2.2A$		53		nC
Gate-Source Charge ^{1,2}	Q_{gs}			13		
Gate-Drain Charge ^{1,2}	Q_{gd}			20		
Turn-On Delay Time ^{1,2}	$t_{d(on)}$	$V_{DS} = 125V, I_D = 1A, V_{GS} = 10V, R_G = 6\Omega$		30		nS
Rise Time ^{1,2}	t_r			200		
Turn-Off Delay Time ^{1,2}	$t_{d(off)}$			75		
Fall Time ^{1,2}	t_f			120		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_c = 25^\circ\text{C}$)						
Continuous Current	I_s				18	A
Pulsed Current ³	I_{SM}				72	
Forward Voltage ¹	V_{SD}	$I_F = I_s, V_{GS} = 0V$			1.3	V
Reverse Recovery Time	t_{rr}	$I_F = 4.4A, dI_F/dt = 100A/\mu\text{s}$		200		nS
Reverse Recovery Charge	Q_{rr}				1.2	μC

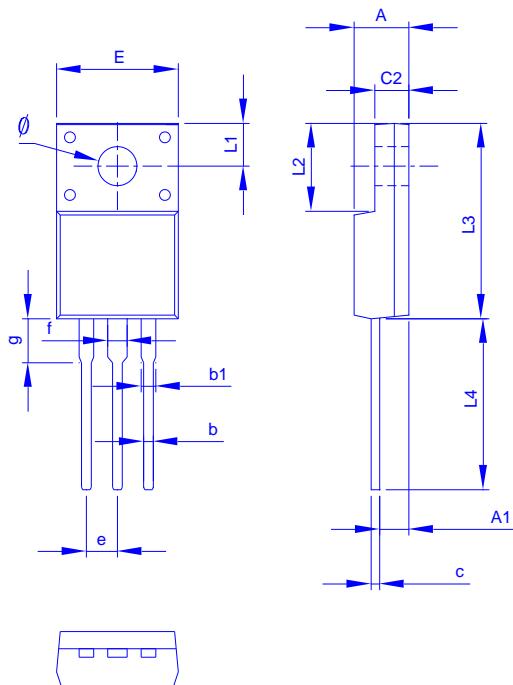
¹Pulse test : Pulse Width $\leq 300\ \mu\text{sec}$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.³Pulse width limited by maximum junction temperature.

Ordering & Marking Information:

Device Name: EMDB0N25F for TO-220F



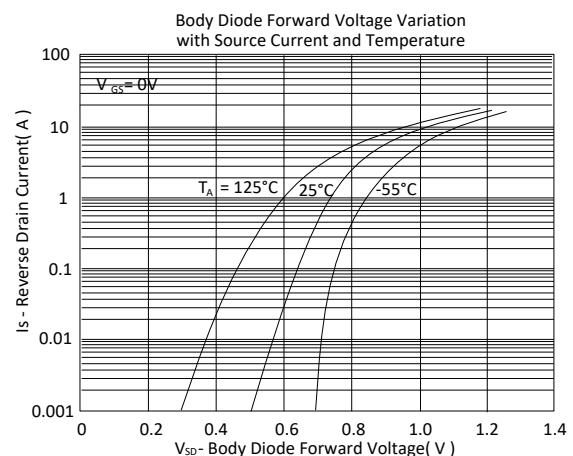
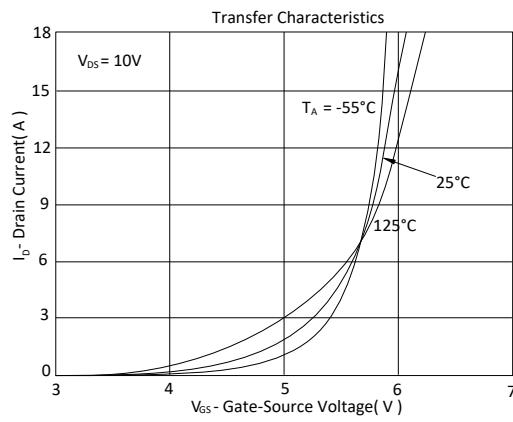
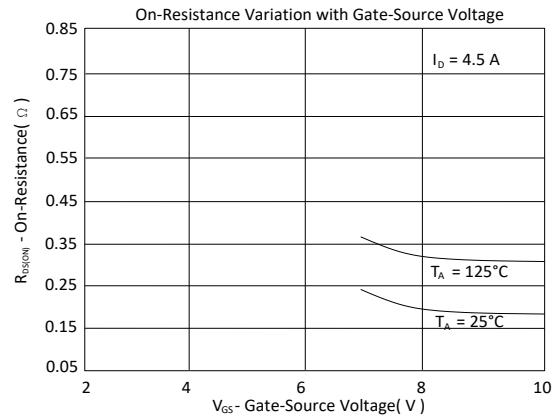
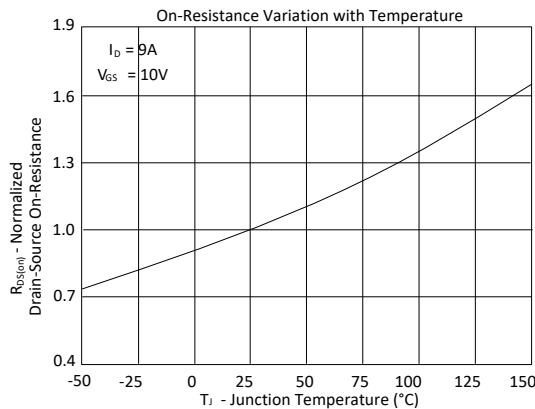
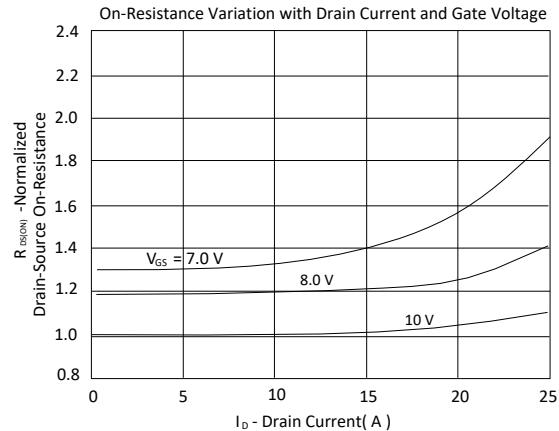
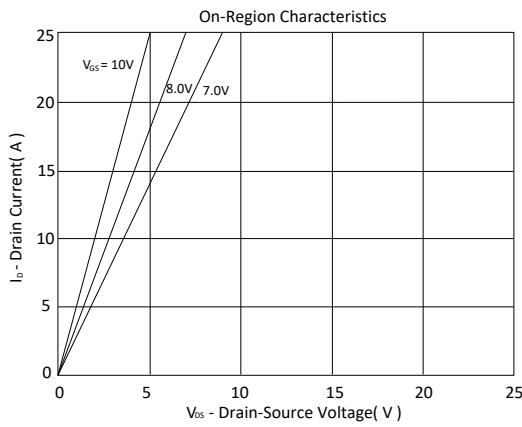
Outline Drawing

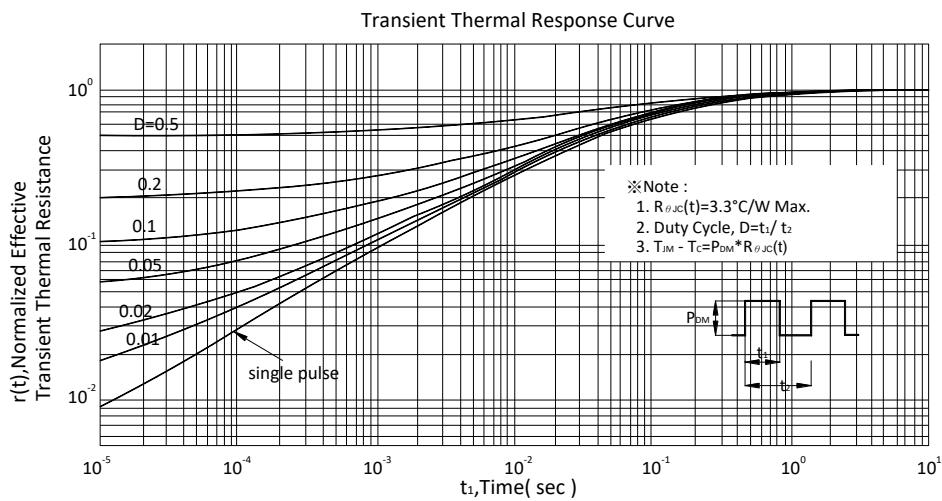
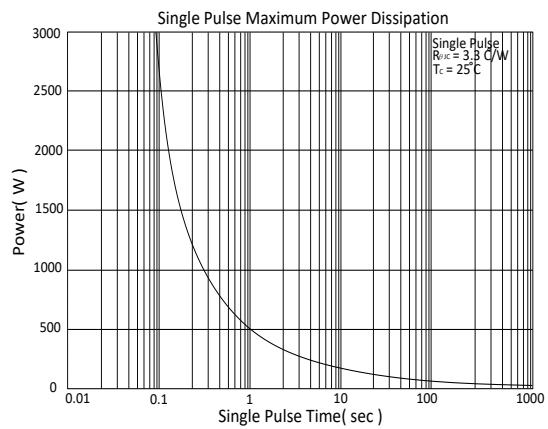
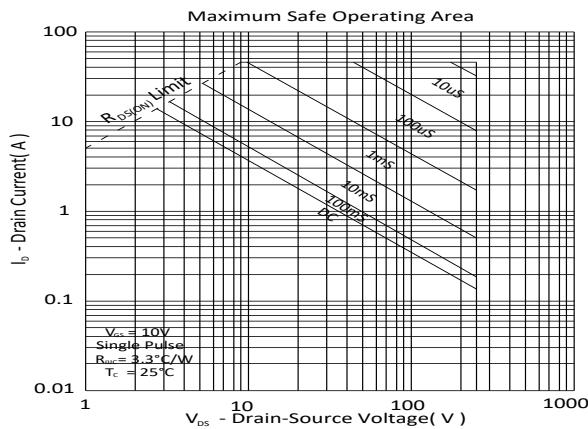
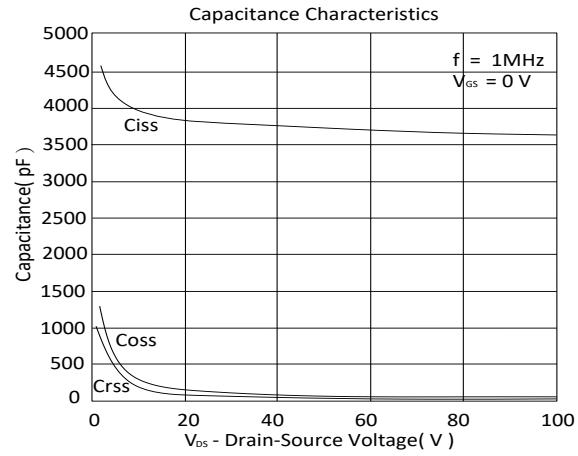
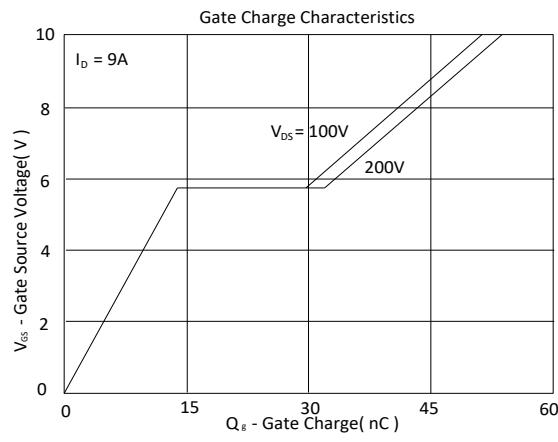


Dimension in mm

Dimension	A	A1	b	b1	c	c2	E	L1	L2	L3	L4	Ø	e	f	g
Min.	4.3	2.49	0.5	1.1	0.4	2.34	9.96	2.7	6.48	14.8	12.65	3	2.44	1.17	2.93
Typ.	4.5	2.59	0.8	1.3	0.5	2.54	10.1	3.25	6.68	15.87	12.98	3.1	2.54	1.28	3.03
Max.	4.9	2.96	0.95	1.6	0.75	3.2	10.36	3.45	6.9	16.2	13.5	3.38	2.64	1.75	4

TYPICAL CHARACTERISTICS







◆ Tube Information: 50pcs/Tube (1000pcs/Box)

